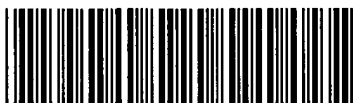


Search Notes

Application/Control No.

10/605,462

Examiner

David Mis

Applicant(s)/Patent under
Reexamination

CHEN, YU-CHEN

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
331	45, 57, 74, 75	3/17/2005	DM
327	116,		
	119-123,		
	291, 193,		
	294, 298		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
as	above	3/17/2005	DM

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR